

NASA Technical Memorandum 100619

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(NASA-TM-100619) X-RAY PRODUCTION IN LOW
ENERGY PROTON STOPPING (NASA) 12 PCSCCL 20H

N88-23582

G3/72 Unclass
0145972

April 1988

NASA

National Aeronautics and
Space Administration

Langley Research Center
Hampton, Virginia 23665-5225

X-RAY PRODUCTION IN LOW ENERGY PROTON STOPPING

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Abstract

The X-ray yields of stopping protons in an iron-nickel-cobalt alloy are calculated for use in predicting radiation damage in encased electronic devices.

INTRODUCTION

It is observed in some electronic devices that radiation effects result from low energy protons stopping in the external casing materials without crossing the device sensitive region (refs. 1 and 2). In order to explain this phenomenon, secondary radiations produced in the casing material are suspect. The most likely radiations to penetrate the casing material are the X-rays produced by proton impact. In the present note, the X-ray yields from stopping protons in an iron-nickel-cobalt alloy are calculated. The methods are easily extended to other materials.

X-RAY PRODUCTION CROSS SECTIONS

The K-shell and L-shell ionization cross sections for iron, cobalt, and nickel have been evaluated with the results given in Tables 1 and 2, using the work of Khandelwal, Choi, and Merzbacher (ref. 3). The X-ray fluorescence yield is in competition with Auger and Coster-Kronig transitions, and the fractional fluorescence yield is given in refs. 4, 5, and 6. The K-shell and L-shell fractional yields are shown in Table 3.

LOW ENERGY PROTON TRANSPORT

If nuclear processes and straggling are neglected, the proton transport equation is given as

$$\left[\frac{\partial}{\partial x} - \frac{\partial}{\partial E} S(E) \right] \psi(x, E) = 0 \quad (1)$$

where $\psi(x, E)$ is proton flux at x of energy E . The solution is given as

$$\psi(x, E) = \frac{S[\epsilon(x + R(E))]}{S(E)} \psi[0, \epsilon(x + R(E))] \quad (2)$$

where $r(E) = \int_0^E dE'/S(E')$ and $\epsilon(x)$ is inverse of $R(E)$. The result (equation 2) can now be used to calculate the X-ray yields $Y_X(x)$ as

$$Y_X(x) = \bar{w}_X \int_0^\infty \sigma_X(E) \psi(x, E) dE \quad (3)$$

where $\sigma_X(E)$ is the macroscopic ionization cross section and \bar{w}_X is the shield's

fractional fluorescence yield. The yield for a monoenergetic beam of protons is

$$\begin{aligned}
 Y_X(x) &= \bar{w}_X \int_0^\infty \sigma_X(E) \phi_p \frac{S[\varepsilon(x + R(E))]}{S(E)} \delta(\varepsilon[x + R(E)] - E_0) dE \\
 &= \bar{w}_X \int_0^\infty \sigma_X[\varepsilon(r)] \phi_p \delta(x + r - r_0) dr
 \end{aligned} \tag{4}$$

where $r_0 = R(E_0)$ and $r = R(E)$. The result is

$$Y_X(x) = \bar{w}_X \sigma_X[\varepsilon(r_0 - x)] \phi_p \tag{5}$$

as one would presume. The total yield \bar{Y}_X in stopping is then

$$\bar{Y}_X = \bar{w}_X \phi_p \int_0^{r_0} \sigma_X[\varepsilon(r_0 - x)] dx \tag{6}$$

The required functions will now be approximated to evaluate the integral (equation 6).

STOPPING POWER AND CROSS SECTION PARAMETERS

The low energy portion of the stopping power curve was shown by Fermi to be

$$S(E) \approx a \sqrt{E} \tag{7}$$

The stopping power to several MeV is adequately approximated by

$$S(E) = \frac{a\sqrt{E}}{(1 + bE)} \tag{8}$$

and is known to have a maximum at approximately $E_m \approx 100$ keV so that

$$\left. \frac{dS}{dE} \right|_{E_m} = 0 \quad (9)$$

and

$$S_m = S(E_m) \quad (10)$$

are sufficient to determine the coefficients a and b to find

$$S(E) = Z S_m \frac{\sqrt{\frac{E}{E_m}}}{1 + \frac{E}{E_m}} \quad (11)$$

The range is then found to be

$$R(E) = \frac{\sqrt{\frac{E}{E_m}}}{\frac{S_m}{S_m}} \left(1 + \frac{E}{E_m} \right) \quad (12)$$

Assuming the density to be 8.4 g/cm^3 and taking $S_m \approx 246 \text{ keV}/\mu$, we find the ionization cross sections can be reasonably approximated by

$$\sigma_X [E(r)] \approx \sigma_X (E_0) \left(\frac{r}{r_0} \right)^{2.2} \quad (13)$$

which holds below 1 MeV. This gives a total yield of

$$Y_X = \frac{\bar{w}_X}{3.2} r_0 \sigma_X (E_0) \phi_P \quad (14)$$

We have taken the composition of the alloy to be 54 percent Fe, 29 percent Ni, and 17 percent Co to find the K shell fluorescence yield for 1 MeV protons to be

$$\bar{Y}_K = 9 \times 10^{-4} \text{ X-rays/proton} \quad (15)$$

To assess the effects of these X-rays on device performance requires additional transport calculations of the X-rays through the device itself.

CONCLUDING REMARKS

The present formalism provides a means of estimating the X-ray production in proton exposures. The fluorescence yield may be used as source terms in a photon/electron transport code to further evaluate their effects on device performance.

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Table 1 - K-shell Ionization Cross Sections (b) as a Function
of Proton Energy (MeV)

E	Fe	Co	Ni
0.1	0.054	.035	.021
0.5	11.0	8.49	5.86
1.0	70.8	50.3	35.5

Table 2 - L-shell Ionization Cross Sections (b)
as a Function of Proton Energy (MeV)

E	Fe	Co	Ni
0.1	4.27E4	2.71E4	1.62E4
0.5	3.68E5	2.80E5	2.06E5
1.0	5.28E5	4.14E5	3.25E5

Table 3 - Fractional Fluorescence Yield

Element	\bar{w}_K	\bar{w}_L
Fe	0.34	6.4E - 3
Co	~0.37	7.7E - 3
Ni	0.41	9.1E - 3



Report Documentation Page

1. Report No. NASA TM-100619		2. Government Accession No.		3. Recipient's Catalog No.	
4. Title and Subtitle X-Ray Production in Low Energy Proton Stopping			5. Report Date April 1988		
			6. Performing Organization Code		
7. Author(s) J. W. Wilson G. S. Khandelwal N. T. Fogarty			8. Performing Organization Report No.		
			10. Work Unit No. 199-22-76-01		
9. Performing Organization Name and Address NASA Langley Research Center Hampton, VA 23665-5225			11. Contract or Grant No.		
			13. Type of Report and Period Covered Technical Memorandum		
12. Sponsoring Agency Name and Address National Aeronautics and Space Administration Washington, DC 20546-0001			14. Sponsoring Agency Code		
			15. Supplementary Notes J. W. Wilson, Langley Research Center, Hampton, VA G. S. Khandelwal, Old Dominion University, Norfolk, VA N. T. Fogarty, Hampton University, Hampton, VA		
16. Abstract The X-ray yields of stopping protons in an iron-nickel-cobalt alloy are calculated for use in predicting radiation damage in encased electronic devices.					
17. Key Words (Suggested by Author(s)) X-ray production Protons radiation damage			18. Distribution Statement Unclassified - Unlimited Subject Category 54		
19. Security Classif. (of this report) Unclassified		20. Security Classif. (of this page) Unclassified		21. No. of pages 11	22. Price A02